



# STM303N040LSH8H

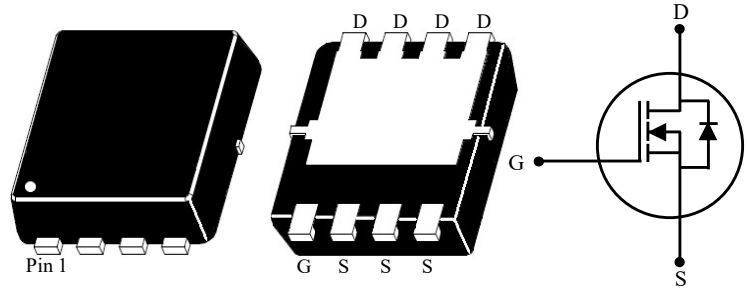
## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- Low  $R_{DS(on)}$
- Suffix "H" indicates Halogen-free parts, ex. STM303N040LSH8H

### PIN CONFIGURATION

DFN3x3-8L



D	Drain
G	Gate
S	Source

### Maximum Ratings ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DS}$	30	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$		
Drain Current	$I_D$	$T_C = 25\text{ }^\circ\text{C}$	48	A
		$T_C = 100\text{ }^\circ\text{C}$	30	
Pulsed Drain Current (Note 1)	$I_{DM}$	280	A	
Avalanche Current	$I_{AS}$	33	A	
Avalanche Energy (Note 2)	$E_{AS}$	54.5	mJ	
Power Dissipation	$P_D$	15.6	W	
Thermal Resistance from Junction to Ambient (Note 3)	$R_{\theta JA}$	50	$^\circ\text{C/W}$	
Thermal Resistance from Junction to Case	$R_{\theta JC}$	8	$^\circ\text{C/W}$	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to + 150	$^\circ\text{C}$	

Note:

1. The data tested by pulsed, pulse width  $\leq 100\mu\text{s}$ , duty cycle  $\leq 2\%$ , Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)} = 150\text{ }^\circ\text{C}$
2. Limited by  $T_{J(MAX)}$ , starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $L = 0.1\text{mH}$ ,  $R_g = 25\Omega$ ,  $I_{AS} = 33\text{A}$ ,  $V_{GS} = 10\text{V}$ .
3. Device mounted on FR-4 substrate PC board, 2oz copper, with 1 inch<sup>2</sup> copper plate in still air.



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### Electrical Characteristics ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise specified)

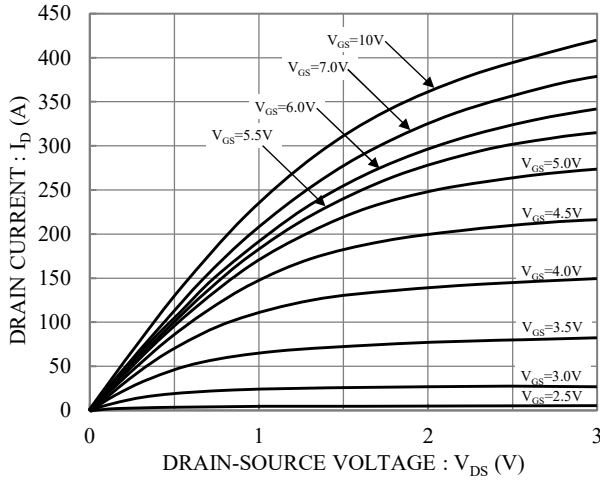
Parameter	Conditions	Symbol	Min.	Typ.	Max.	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}$	$V_{(BR)DSS}$	30	-	-	V
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	$V_{GS(th)}$	1.2	-	2.5	V
Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}$	$I_{DSS}$	-	-	1	$\mu\text{A}$
Gate Leakage Current	$V_{GS} = \pm 20\text{V}$	$I_{GSS}$	-	-	$\pm 100$	nA
Drain-Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 24\text{A}$	$R_{DS(on)}$	-	3.2	4.0	m $\Omega$
	$V_{GS} = 4.5\text{V}, I_D = 12\text{A}$		-	-	5.5	
Forward Transconductance	$V_{DS} = 5\text{V}, I_D = 24\text{A}$	$g_{FS}$	-	27	-	S
<b>Dynamic</b>						
Gate Resistance	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$	$R_g$	-	1	-	$\Omega$
Total Gate Charge	$V_{DS} = 15\text{V}, V_{GS} = 4.5\text{V}, I_D = 24\text{A}$	$Q_g$	-	26.0	-	nC
		$Q_{gs}$	-	53.0	-	
		$Q_{gd}$	-	8.5	-	
Gate-Source Charge	$V_{DS} = 15\text{V}, V_{GS} = 10\text{V}, I_D = 24\text{A}$	$Q_{gs}$	-	8.5	-	pF
Gate-Drain Charge		$Q_{gd}$	-	13.0	-	
Input Capacitance		$C_{iss}$	-	2300	-	
Output Capacitance	$V_{DS} = 15\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$	$C_{oss}$	-	278	-	pF
Reverse Transfer Capacitance		$C_{rss}$	-	229	-	
Turn on Delay Time	$V_{DS} = 15\text{V}, I_D = 24\text{A}$ $V_{GS} = 10\text{V}, R_g = 3.3\Omega$	$t_{d(on)}$	-	18	-	ns
Turn on Rise Time		$t_r$	-	54	-	
Turn off Delay Time		$t_{d(off)}$	-	18	-	
Turn off Fall Time		$t_f$	-	7	-	
<b>Drain-Source Body Diode</b>						
Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 1\text{A}$	$V_{SD}$	-	-	1.2	V
Diode Continuous Forward Current	-	$I_S$	-	-	48	A
Diode Pulse Current		$I_{SM}$	-	-	280	A
Reverse Recovery Time	$I_S = 24\text{A}, di/dt = 100\text{A}/\mu\text{s}$	$t_{rr}$	-	15.5	-	ns
Reverse Recovery Charge		$Q_{rr}$	-	6.4	-	nC



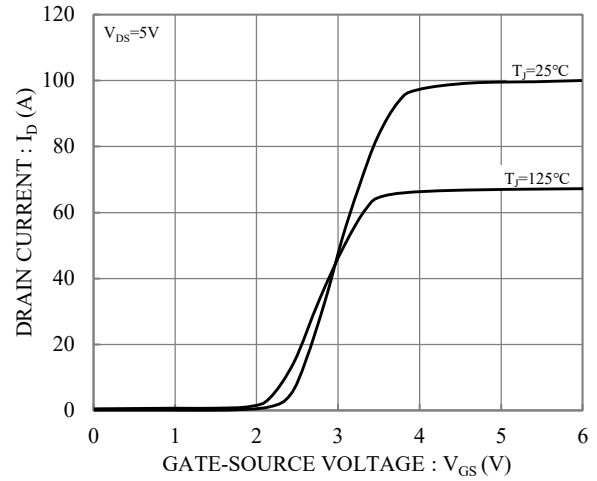
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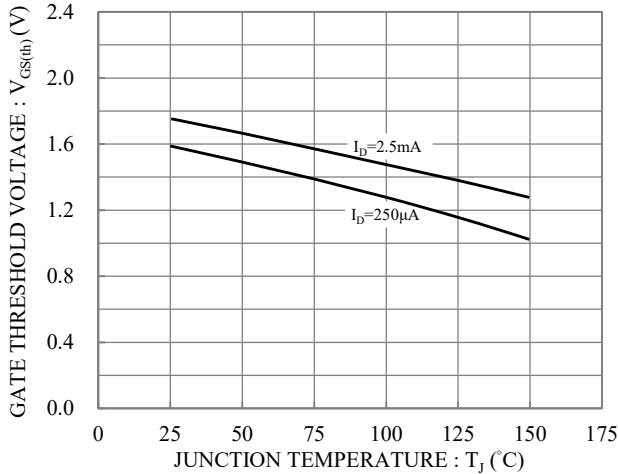
### RATINGS AND CHARACTERISTIC CURVES



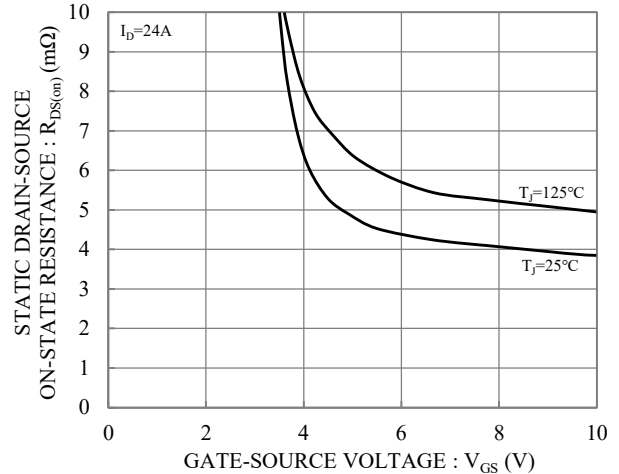
**Fig.1 Typical Output Characteristics**



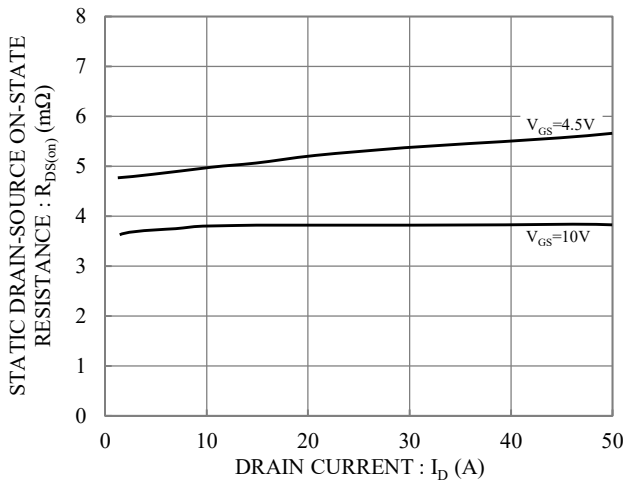
**Fig.2 Typical Transfer Characteristics**



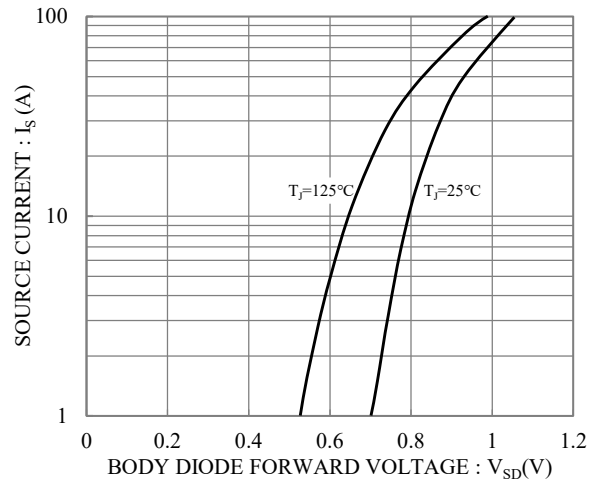
**Fig.3 Gate Threshold Voltage vs. Junction Temperature**



**Fig.4 Static Drain-Source On-State Resistance vs. Gate-Source Voltage**



**Fig.5 Static Drain-Source On-State Resistance vs. Drain Current**

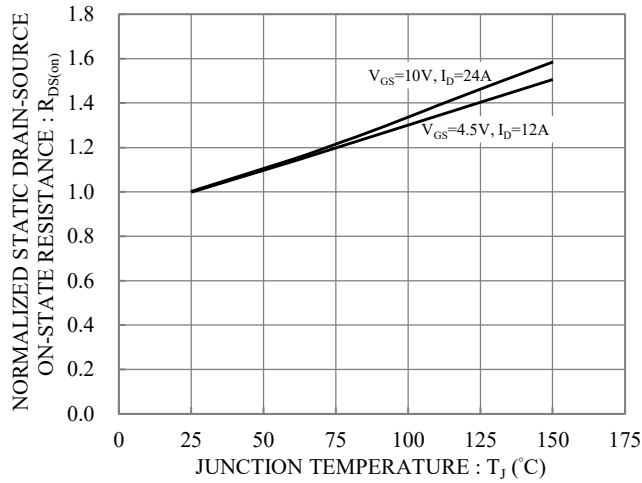


**Fig.6 Body Diode Forward Voltage vs. Source Current**

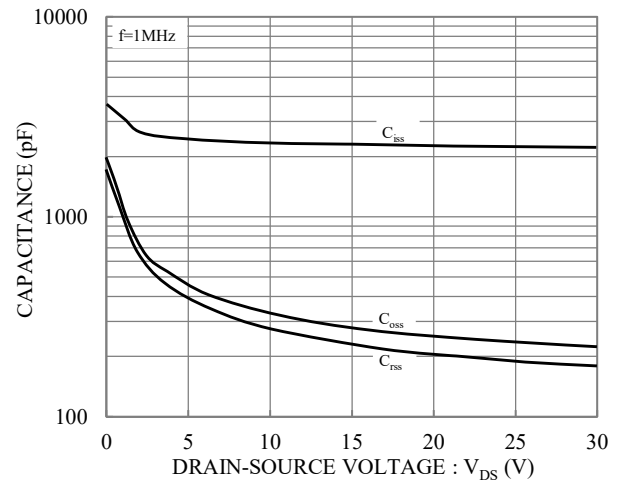


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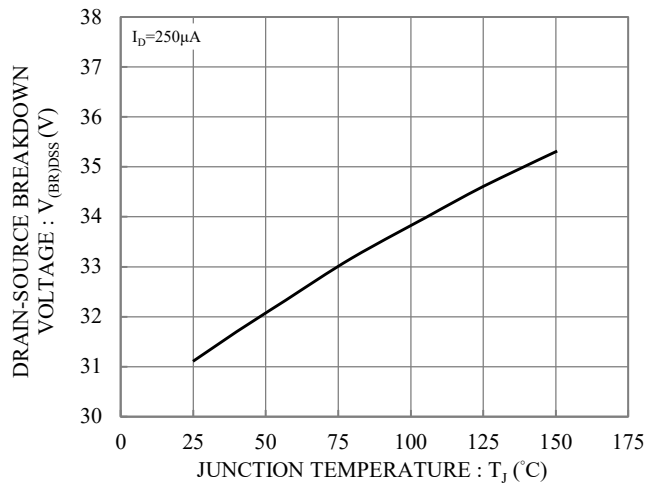
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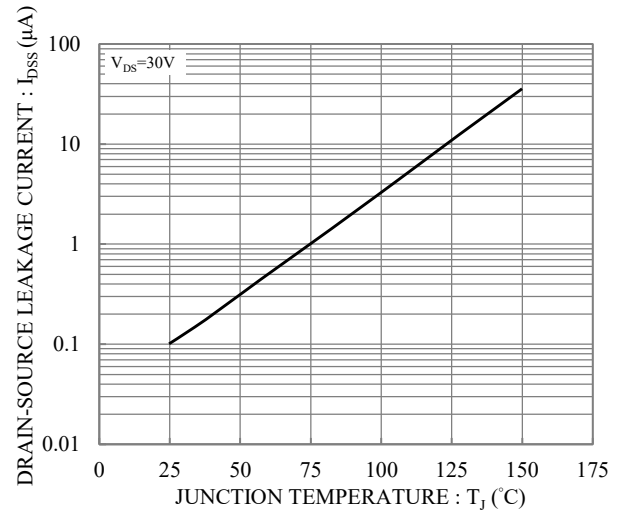
**Fig.7 Drain-Source On-State Resistance vs. Junction Temperature**



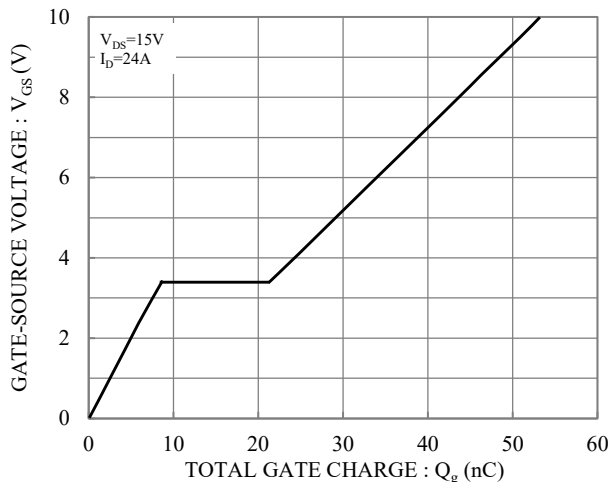
**Fig.8 Capacitance vs. Drain-Source Voltage**



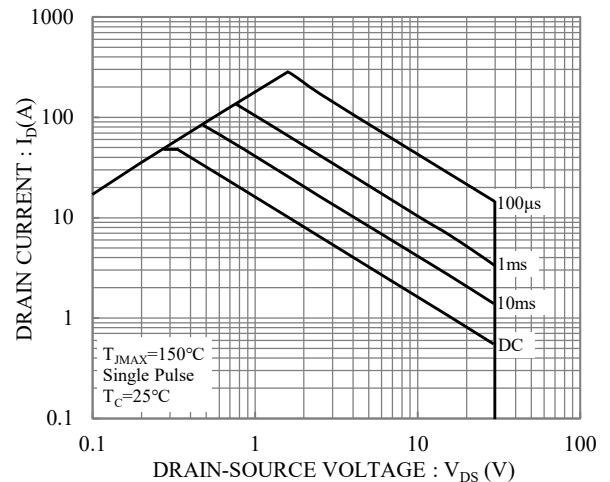
**Fig.9 Breakdown Voltage vs. Junction Temperature**



**Fig.10 Drain-Source Leakage Current vs. Junction Temperature**



**Fig.11 Gate Charge Characteristics**

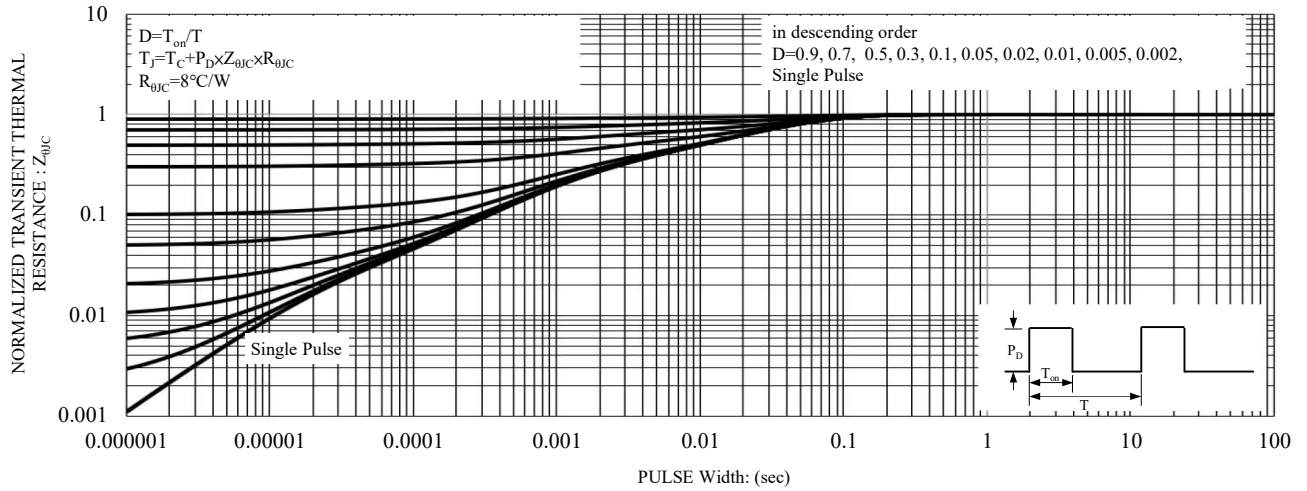


**Fig.12 Safe Operation Area**

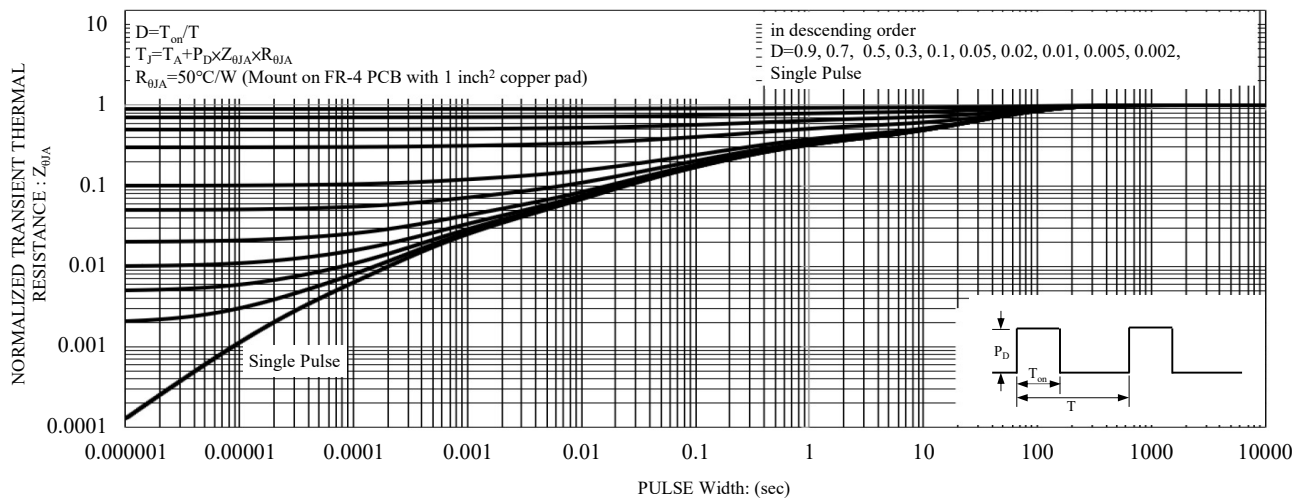


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**Fig.13 Maximum Transient Thermal Impedance**



**Fig.14 Maximum Transient Thermal Impedance**

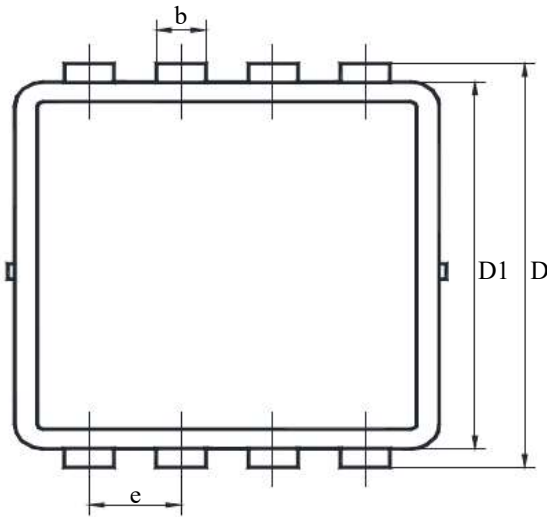


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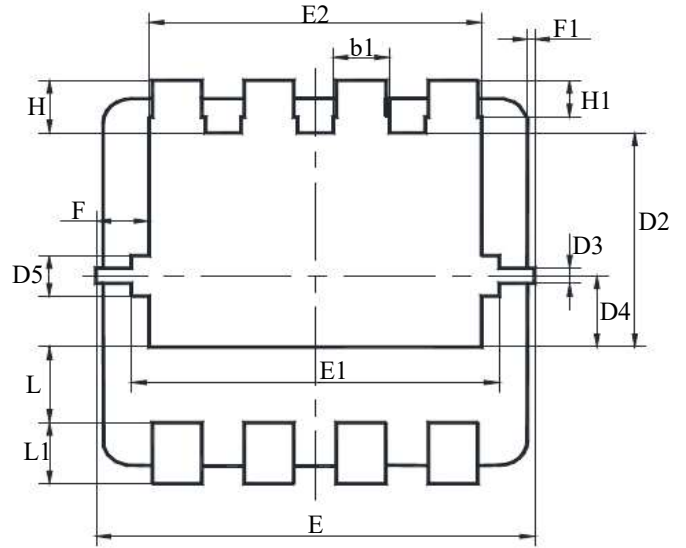
N-Channel Enhancement Mode Field Effect Transistor

## PACKAGE DIMENSION

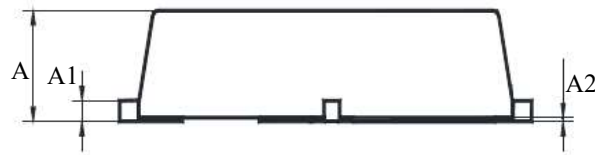
### DFN3×3-8L



Top View



Bottom View



Side View

Symbol	Millimeters		Inches	
	Min	Max	Min	Max
A	0.700	0.900	0.028	0.035
A1	0.100	0.250	0.004	0.010
A2	0.000	0.050	0.000	0.002
b	0.240	0.350	0.009	0.014
b1	0.300	0.500	0.012	0.020
D	3.100	3.300	0.122	0.130
D1	2.900	3.100	0.114	0.122
D2	1.650	1.850	0.065	0.073
D3	0.150	0.250	0.006	0.010
D4	0.480	0.680	0.019	0.027
D5	0.230	0.430	0.009	0.017
E	3.000	3.200	0.118	0.126
E1	2.500	2.700	0.098	0.106
E2	2.400	2.600	0.094	0.102
e	0.600	0.700	0.024	0.028
F	0.275	0.475	0.011	0.019
F1	0.000	0.100	0.000	0.004
L	0.520	0.720	0.020	0.028
L1	0.300	0.500	0.012	0.020
H	0.330	0.530	0.013	0.021
H1	0.200	0.400	0.008	0.016



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## SUGGESTED SOLDER PAD LAYOUT

